

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>10027992</u>	Prepared by <u>PAP</u>	Tracking Number <u>05984745</u>	
Examiner-GAU <u>Kastler-1742</u>	Date <u>9/1/04</u>	Week Date <u>7/26/04</u>	
	No. of queries <u>1</u>	IFW	

## JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	<input checked="" type="checkbox"/> PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

## SPECIFICATION

- a. Page Missing
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## CLAIMS

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## RESPONSE

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. /M34006DIV	PRIORITY SERIAL NO. 09/014,714
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Janine K. Kardokus et al.	
				PRIORITY FILING DATE November 15, 2000	PRIORITY GROUP 1742

  

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
SK	AA	4,675,837	06/87	Hosoda et al.	1	1	
	AB	4,814,053	03/89	Shimokawato			
	AC	4,984,856	01/91	Tadigawa et al.			
	AD	5,023,698	06/91	Kobayashi et al.			
	AE	5,046,617	11/91	Tanemoto et al.			
	AF	5,077,005	12/91	Kato			
	AG	5,314,651	05/94	Kutwicki			
	AH	5,719,447	02/98	Gardner			
	AI	5,833,820	11/98	Dubin			
	AJ	5,895,342	04/99	Dubin			
SU	AK	5,972,192	10/99	Dubin et al.	1	1	
	AL	6,093,966	07/00	Venkatesan et al.			

  

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
8P 92 SC	AM	6323442	9/30/83	1	1		L
	AN	363033174	02/12/88				L
	AO	0073531 A2	12/7/00				0
	AP						
	AQ						

  

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
SU	AR		Masafumi, T., "Binary Alloy Phase Diagrams". Vol. 1, American Society for Metals, Ohio 1986, pp. 18-19, 928-929, 936-937, 964-965.
64	AS		West, C., "International Critical Tables of Numerical Data, Physics, Chemistry and Technology", National Research Council of the USA, McGraw-Hill Book Co., Inc. 1933, 6 pages.
R	AT		Pickman, K. et al., "Total Sputtering Yield of Ag/Ce Alloys for Low Energy Argon Ions", Nucl. Instrum. Methods Phys. Res., Sect. B (1996), Vol. 108(3), pp. 290-299.

  

EXAMINER <b>S. Kastler</b>	DATE CONSIDERED <b>7-04</b>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.